

TOSHIBA CMOS DIGITAL INTEGRATED CIRCUIT SILICON MONOLITHIC

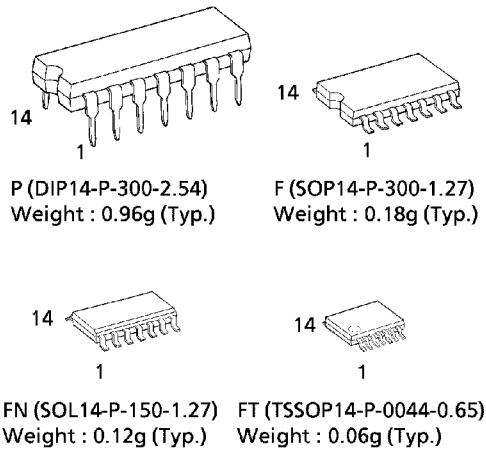
TC4011BP, TC4011BF, TC4011BFN, TC4011BFT

TC4011B QUAD 2 INPUT NAND GATE

The TC4011B is 2-input positive logic NAND gate respectively.

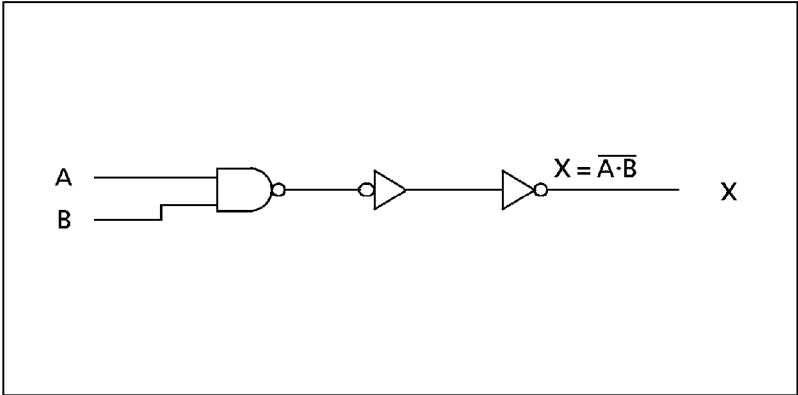
Since all the outputs of these gates are provided with the inverters as buffers, the input/output characteristics have been improved and the variation of propagation delay time due to the increase in load capacity is kept down to the minimum.

(Note) The JEDEC SOP (FN) is not available in Japan.

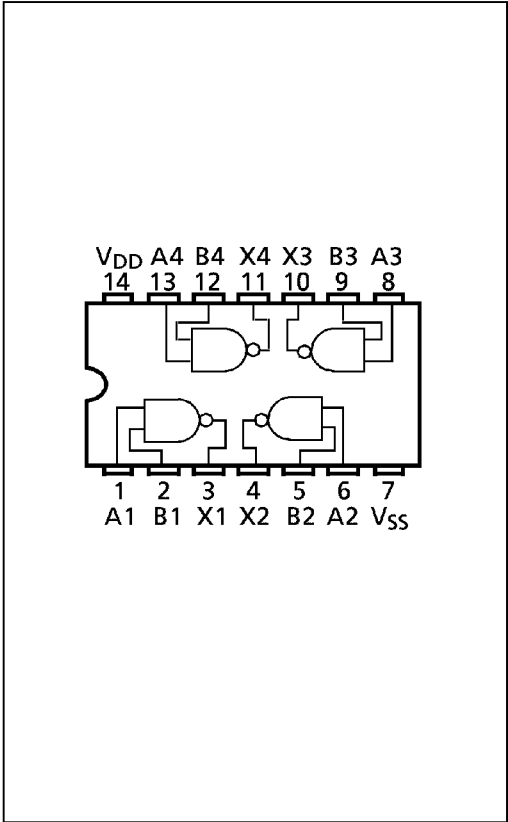


CHARACTERISTIC	SYMBOL	RATING	UNIT
DC Supply Voltage	V_{DD}	$V_{SS} - 0.5 \sim V_{SS} + 20$	V
Input Voltage	V_{IN}	$V_{SS} - 0.5 \sim V_{DD} + 0.5$	V
Output Voltage	V_{OUT}	$V_{SS} - 0.5 \sim V_{DD} + 0.5$	V
DC Input Current	I_{IN}	± 10	mA
Power Dissipation	P_D	300 (DIP) / 180 (SOIC)	mW
Operating Temperature Range	T_{opr}	$-40 \sim 85$	$^{\circ}\text{C}$
Storage Temperature Range	T_{stg}	$-65 \sim 150$	$^{\circ}\text{C}$

LOGIC DIAGRAM



PIN ASSIGNMENT (TOP VIEW)



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RECOMMENDED OPERATING CONDITIONS ($V_{SS} = 0V$)

CHARACTERISTIC	SYMBOL	TEST CONDITION	MIN.	TYP.	MAX.	UNIT
DC Supply Voltage	V_{DD}		3	—	18	V
Input Voltage	V_{IN}		0	—	V_{DD}	V

STATIC ELECTRICAL CHARACTERISTICS ($V_{SS} = 0V$)

CHARACTERISTIC	SYM-BOL	TEST CONDITION	V_{DD} (V)	- 40°C		25°C			85°C		UNIT
				MIN.	MAX.	MIN.	TYP.	MAX.	MIN.	MAX.	
High-Level Output Voltage	V_{OH}	$ I_{OUT} < 1\mu A$ $V_{IN} = V_{SS}, V_{DD}$	5	4.95	—	4.95	5.00	—	4.95	—	V
			10	9.95	—	9.95	10.00	—	9.95	—	
			15	14.95	—	14.95	15.00	—	14.95	—	
Low-Level Output Voltage	V_{OL}	$ I_{OUT} < 1\mu A$ $V_{IN} = V_{SS}, V_{DD}$	5	—	0.05	—	0.00	0.05	—	0.05	V
			10	—	0.05	—	0.00	0.05	—	0.05	
			15	—	0.05	—	0.00	0.05	—	0.05	
Output High Current	I_{OH}	$V_{OH} = 4.6V$	5	-0.61	—	-0.51	-1.0	—	-0.42	—	mA
		$V_{OH} = 2.5V$	5	-2.50	—	-2.10	-4.0	—	-1.70	—	
		$V_{OH} = 9.5V$	10	-1.50	—	-1.30	-2.2	—	-1.10	—	
		$V_{OH} = 13.5V$	15	-4.00	—	-3.40	-9.0	—	-2.80	—	
		$V_{IN} = V_{SS}, V_{DD}$									
Output Low Current	I_{OL}	$V_{OL} = 0.4V$	5	0.61	—	0.51	1.2	—	0.42	—	mA
		$V_{OL} = 0.5V$	10	1.50	—	1.30	3.2	—	1.10	—	
		$V_{OL} = 1.5V$	15	4.00	—	3.40	12.0	—	2.80	—	
		$V_{IN} = V_{SS}, V_{DD}$									
Input High Voltage	V_{IH}	$V_{OUT} = 0.5V$	5	3.5	—	3.5	2.75	—	3.5	—	V
		$V_{OUT} = 1.0V$	10	7.0	—	7.0	5.50	—	7.0	—	
		$V_{OUT} = 1.5V$	15	11.0	—	11.0	8.25	—	11.0	—	
		$ I_{OUT} < 1\mu A$									
Input Low Voltage	V_{IL}	$V_{OUT} = 4.5V$	5	—	1.5	—	2.25	1.5	—	1.5	V
		$V_{OUT} = 9.0V$	10	—	3.0	—	4.50	3.0	—	3.0	
		$V_{OUT} = 13.5V$	15	—	4.0	—	6.75	4.0	—	4.0	
		$ I_{OUT} < 1\mu A$									
Input Current	"H" Level	I_{IH}	$V_{IH} = 18V$	18	—	0.1	—	10^{-5}	0.1	—	μA
	"L" Level	I_{IL}	$V_{IL} = 0V$	18	—	-0.1	—	-10^{-5}	-0.1	—	
Quiescent Supply Current	I_{DD}	$V_{IN} = V_{SS}, V_{DD}^*$	5	—	0.25	—	0.001	0.25	—	7.5	μA
			10	—	0.50	—	0.001	0.50	—	15.0	
			15	—	1.00	—	0.002	1.00	—	30.0	

* All valid input combinations.

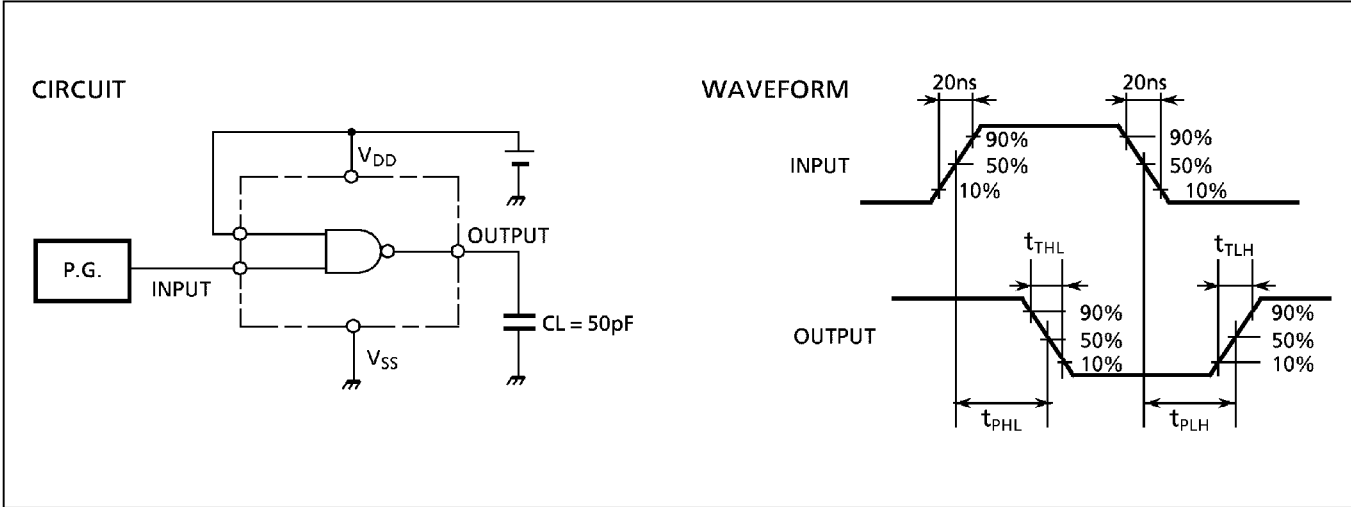
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DYNAMIC ELECTRICAL CHARACTERISTICS (Ta = 25°C, Vss = 0V, CL = 50pF)

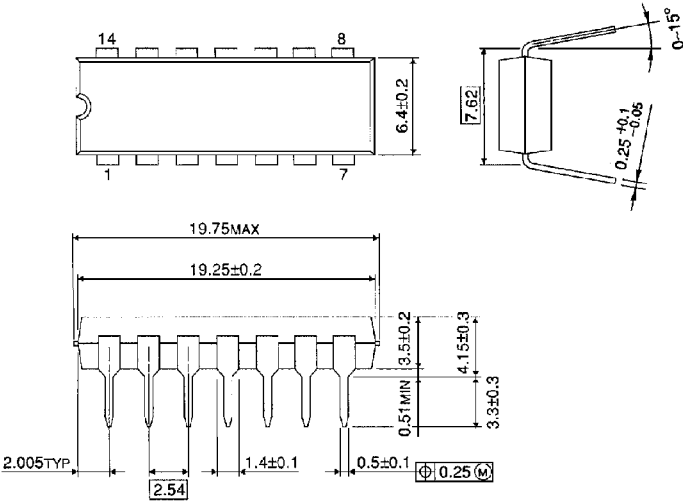
CHARACTERISTIC	SYMBOL	TEST CONDITION	$V_{DD}(V)$	MIN.	TYP.	MAX.	UNIT
Output Transition Time	t_{TLH}		5	—	70	200	ns
			10	—	35	100	
			15	—	30	80	
Output Transition Time	t_{THL}		5	—	70	200	
			10	—	35	100	
			15	—	30	80	
Propagation Delay Time	t_{pLH}		5	—	65	200	
			10	—	30	100	
			15	—	25	80	
Propagation Delay Time	t_{pHL}		5	—	65	200	
			10	—	30	100	
			15	—	25	80	
Input Capacitance	C_{IN}			—	5	7.5	pF

CIRCUIT AND WAVEFORM FOR MEASUREMENT OF DYNAMIC CHARACTERISTICS



DIP 14PIN OUTLINE DRAWING (DIP14-P-300-2.54)

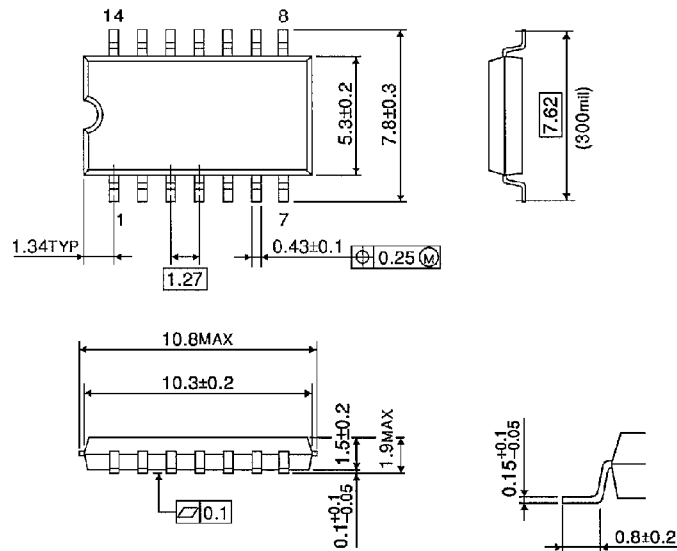
Unit in mm



Weight : 0.96g (Typ.)

SOP 14PIN (200mil BODY) OUTLINE DRAWING (SOP14-P-300-1.27)

Unit in mm

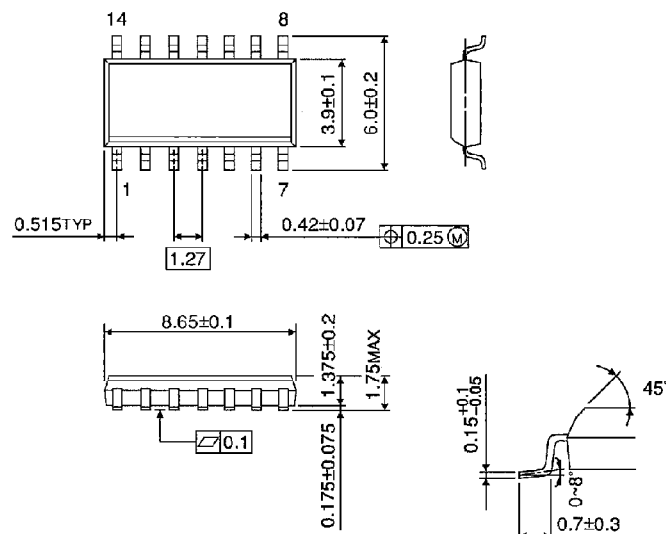


Weight : 0.18g (Typ.)

SOP 14PIN (150mil BODY) OUTLINE DRAWING (SOL14-P-150-1.27)

Unit in mm

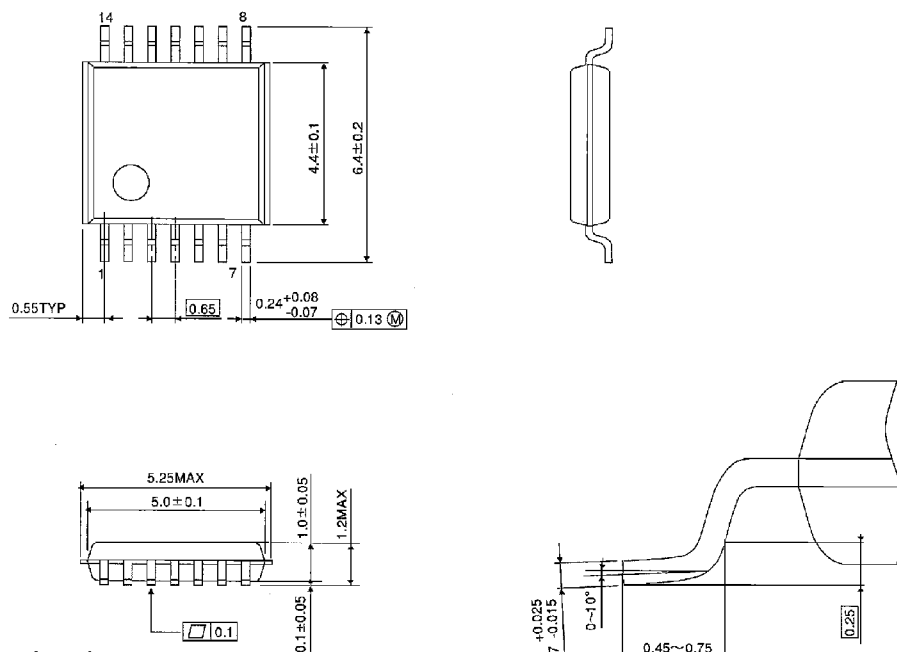
(Note) This package is not available in Japan.



Weight : 0.12g (Typ.)

TSSOP 14PIN (170mil BODY) OUTLINE DRAWING (TSSOP14-P-0044-0.65)

Unit in mm



Weight : 0.06g (Typ.)